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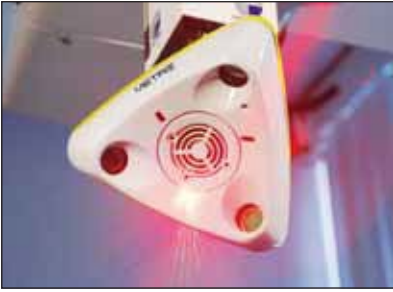
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XC65Dx(-LS) Digital Cross Scanners



The ultimate scanner
for feature measurement and more

Features and benefits



Benefits

- Full 3D capture of complex surfaces and features geometry in a single scan
- Scans any material without spraying
- Faster feature inspection by eliminating scanner re-orientation
- Easy macro-based part programming accelerates measurement preparation
- Seamless retrofit with most leading CMM brands

Key Features

- Patented multi-stripe laser technology observes part from 3 directions
- High-speed digital technology boosts scanning frequency
- Unique point-per-point laser intensity adaptation
- Non-contact laser scanning is ideal to measure flexible or fragile parts
- XC65Dx-LS long stand-off variant for optimum capture into deep pockets and slots, and accessing other hard-to-reach locations

Applications

- Sheet metal vehicle body parts
- Driveline casting inspection (engine castings, etc.)
- Plastic molding and blow molding (composite fuel tanks, plastic body parts, etc.)
- Inspection of 2D and complex 3D features
- Gap and flush of door/fender splines

Technical specifications

	XC65Dx	XC65Dx-LS
Scan speed	Cross Scanner mode: 3 x 25,000pts/s Line scanner mode: 1 x 75,000pts/s 75 lines/s	
Width of view	3x65mm (3x2.56")	3x65mm (3x2.56")
Depth of view	3x65mm (3x2.56")	3x65mm (3x2.56")
Stand-off distance	75mm (2.95")	170mm (6.69")
Probing error	12µm (0.00047")	15µm (0.00059")
Multi-stylus test (MPE _{av}) ¹	9µm (0.00035")	9µm (0.00035")
Dimensions	155x86x142mm (6.1x3.4x5.6")	155x86x142mm (6.1x3.4x5.6")
Weight (approx.)	440g (0.97lbs)	480g (1.06lbs)
CMM mounting	Renishaw PH10M(Q) motorized indexing probe head with Multiwire	
Laser class	2M (Visible)	

¹ Comparable to EN/ISO 10360-5, for a CMM with accuracy of 2µm + L/350 or better



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